1. Record Nr. UNINA9910876645703321 Autore Jenkins Ron <1932-> **Titolo** X-ray fluorescence spectrometry / / Ron Jenkins New York,: Wiley, c1999 Pubbl/distr/stampa **ISBN** 1-283-59302-5 9786613905475 1-118-52086-6 1-118-52101-3 1-118-52104-8 Edizione [2nd ed.] Descrizione fisica 1 online resource (230 p.) Collana Chemical analysis; ; v. 152 Disciplina 543/.08586 Soggetti X-ray spectroscopy Fluorescence spectroscopy Lingua di pubblicazione Inglese **Formato** Materiale a stampa Livello bibliografico Monografia Note generali "A Wiley-Interscience publication." Includes bibliographical references and index. Nota di bibliografia Nota di contenuto X-Ray Fluorescence Spectrometry; CONTENTS; PREFACE TO THE FIRST EDITION: PREFACE TO THE SECOND EDITION: CUMULATIVE LISTING OF VOLUMES IN SERIES; CHAPTER 1 PRODUCTION AND PROPERTIES X-RAYS: 1.1 Introduction: 1.2 Continuous Radiation: 1.3 Characteristic Radiation; 1.4 Absorption of X-Rays; 1.5 Coherent and Incoherent Scattering; 1.6 Interference and Diffraction; Bibliography; CHAPTER 2 INDUSTRIAL APPLICATIONS OF X-RAYS; 2.1 Introduction; 2.2 Diagnostic Uses of X-Rays; 2.3 Tomography; 2.4 Level and Thickness Gauging; 2.5 X-Ray Thickness Gauging; 2.6 Nondestructive Testing 2.7 Security Screening Systems 2.8 X-Ray Lithography; 2.9 X-Ray Astronomy; Bibliography; CHAPTER 3 X-RAY DIFFRACTION; 3.1 Use of X-Ray Diffraction to Study the Crystalline State; 3.2 The Powder Method; 3.3 Use of X-Ray Powder Cameras; 3.4 The Powder Diffractometer; 3.5 Qualitative Applications of the X-Ray Powder Method; 3.6 Quantitative Methods in X-Ray Powder Diffraction; 3.7 Other Applications of X-Ray Diffraction; Bibliography; CHAPTER 4 X-RAY SPECTRA; 4.1 Introduction; 4.2 Electron Configuration of the

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## Sommario/riassunto

X-ray fluorescence spectroscopy, one of the most powerful and flexible techniques available for the analysis and characterization of materials today, has gone through major changes during the past decade. Fully revised and expanded by 30%, X-Ray Fluorescence Spectrometry, Second Edition incorporates the latest industrial and scientific trends in all areas. It updates all previous material and adds new chapters on such topics as the history of X-ray fluorescence spectroscopy, the design of X-ray spectrometers, state-of-the-art applications, and X-ray spectra. Ron Jenkins draws on his exte